Shock and Vibration Qualification Testing
For
FCC8/FSC8

Test Report

Client : Samtec Inc.(HuiZhou) Limited
Address : Huangxi Industrial Park, Shiwan Town, Boluo County, Huizhou City, Guangdong Province, China

Report on the submitted sample said to be:

Sample Name	: Connector
Sample Description	: Normal
Part Number	: FCC8-20-01-L-S-A/FSC8-20-01-L-S-A
Amount of Sample	: 12 pcs
Sample Received Date	: Mar. 01, 2010
Sample tested Date	: Mar. 19, 2010～Mar. 27, 2010

Test Requested: (As requested by the client, please see following sheets in detail.)

Group	Test Sequence	Test Item
Seq. (c) (015～022)	1	Low Level Contact Resistance (LLCR)
	2	Mechanical shock test
	3	Low Level Contact Resistance (LLCR)
	4	Random Vibration Test
	5	Low Level Contact Resistance (LLCR)
Seq. (d) (023～026)	1	Mechanical shock test
	2	Random Vibration Test

Test Results: Please see the attached sheets.

Inspected by: Ivan Sun Engineer

Approved by: Stephen Lee Lab Supervisor

Approved date: Sept. 29, 2010

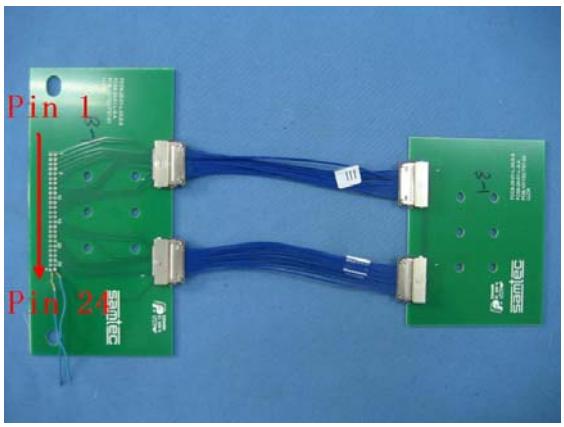
Data Summary:

Group	Test Sequence	Test Item	Requirement	Result
Seq. (c) (015～022)	1	Low Level Contact Resistance (LLCR)	△R≤15 mΩ No damage	Pass
	2	Mechanical shock test		
	3	Low Level Contact Resistance (LLCR)		
	4	Random Vibration Test	△R≤15 mΩ No damage	Pass
	5	Low Level Contact Resistance (LLCR)		
Seq. (d) (023～026)	1	Mechanical Shock	No damage	Pass
			0.1 microsecond	Pass
	2	Random Vibration	No damage	Pass
			0.1 microsecond	Pass

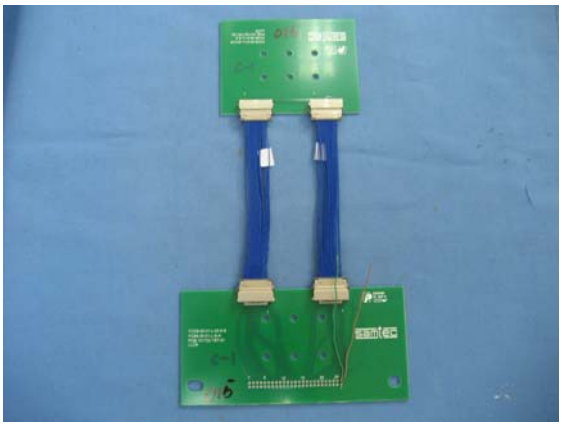
Tested Samples:

Test Seq.	Sample No.	Customer No.	Sample Name	Quantity
Seq. (c)	015～022	C-1～C-8	Connector	8 pcs
Seq. (d)	023～026	D-1～D-4	Connector	4 pcs

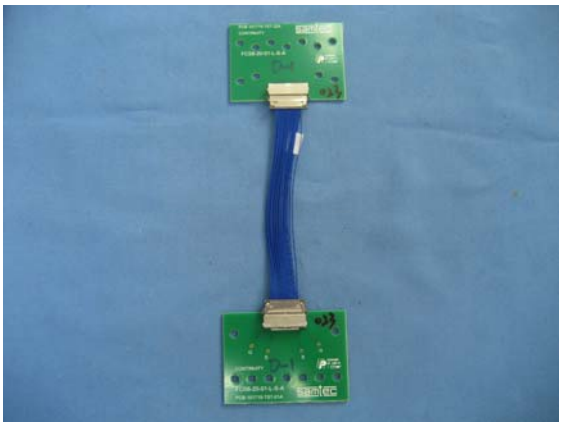
Pin No. of Sample:



Sample Photos before the Test:



Seq. (c)



Seq. (d)

Test Seq. (c)

Test Item 1: Low Level Contact Resistance (LLCR)

(1) Test Equipment:

Sample No.	Model	Serial No	Valid Date to
Milliohmmeter	4338B	BTTEELSZ20034	Feb. 13, 2011

(2) Environmental Conditions:

Temperature: 25℃ Humidity: 51%RH

(3) Reference Standard: EIA-364-23B-2000

(4) Tested Sample: 015~022

(5) Test Condition:

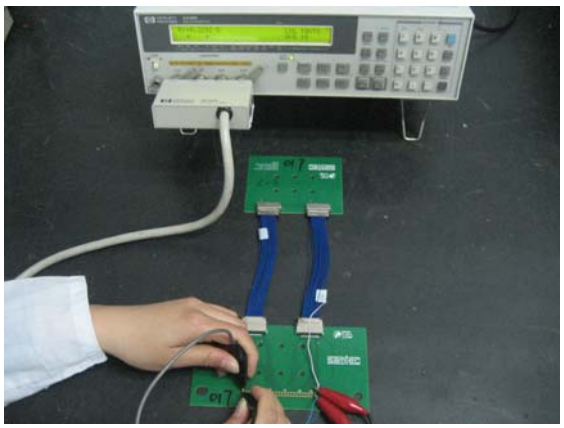
The test performed in accordance to the criteria listed above, and under the conditions as below:

---Test Current: 10 milliamps max

--- Measure and record the Low Level Contact Resistance

Test Results: Please see the appendix from page 35 to page 42.

Test Photo:



Test Seq. (c)

Test Item 2: Mechanical shock test

(1) Test Equipment:

Name	Model	Serial No	Valid Date to
Mechanical Shock Test System	DP-1200-45	BTTEELSZ20033	May. 25, 2010

(2) Environmental Conditions:

Temperature: 24℃ Humidity: 52%RH

(3) Reference Standard: EIA-364-27B-1996

(4) Tested Sample: 015~022

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

---Wave form: Half-sine

---Acceleration: 100 g_n

--- Pulse duration: 6 ms

---Direction: Axis ±X, ±Y, ±Z

---Number of shocks: 3 shocks /axis, 18 times in total

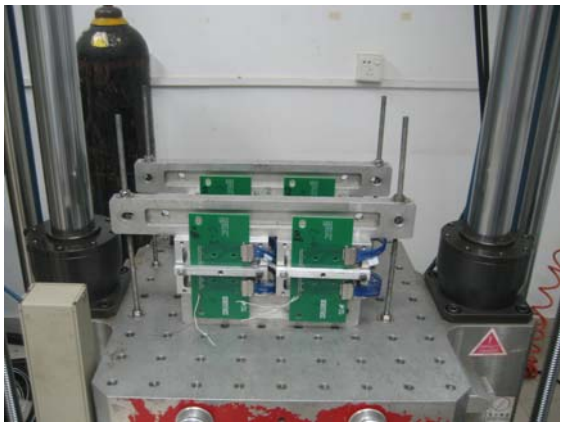
(7) Acceptance criteria:

---There shall be no evidence of physical damage to the tested samples.

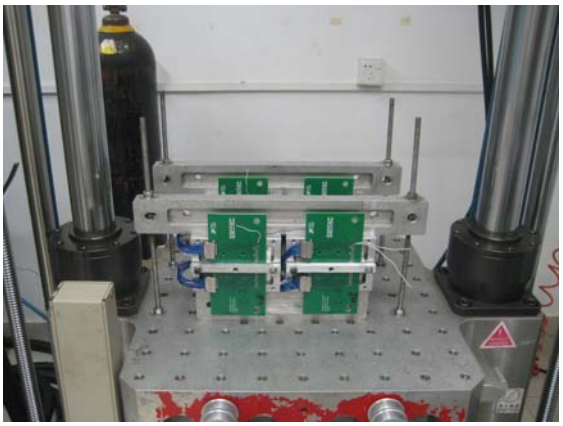
(8) Note: The samples are divided into 2 groups (Group 1: 015~018 and Group 2: 019~022) for the test.

Test Results: There was no physical damage to the tested samples after the test.

Test Photos:



Axis +X



Axis -X

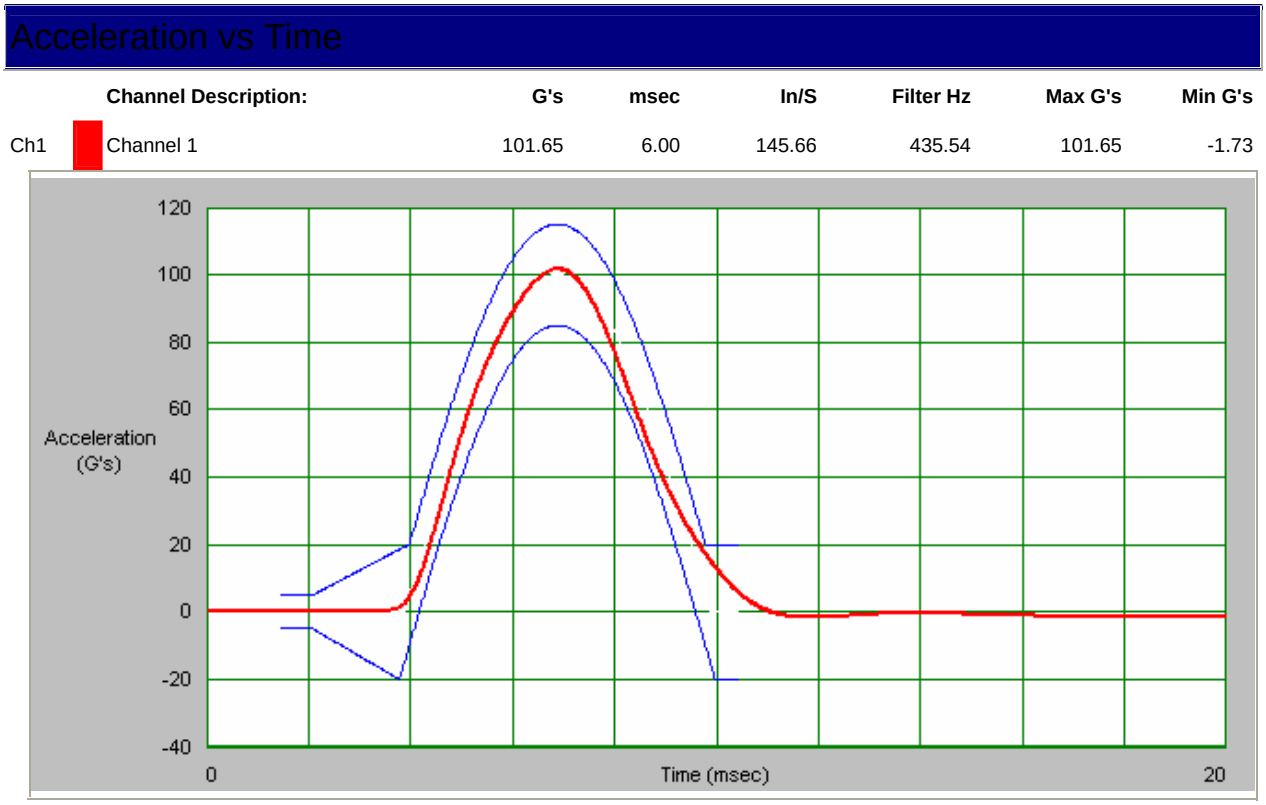
Axis +Y

Axis -Y

Axis +Z

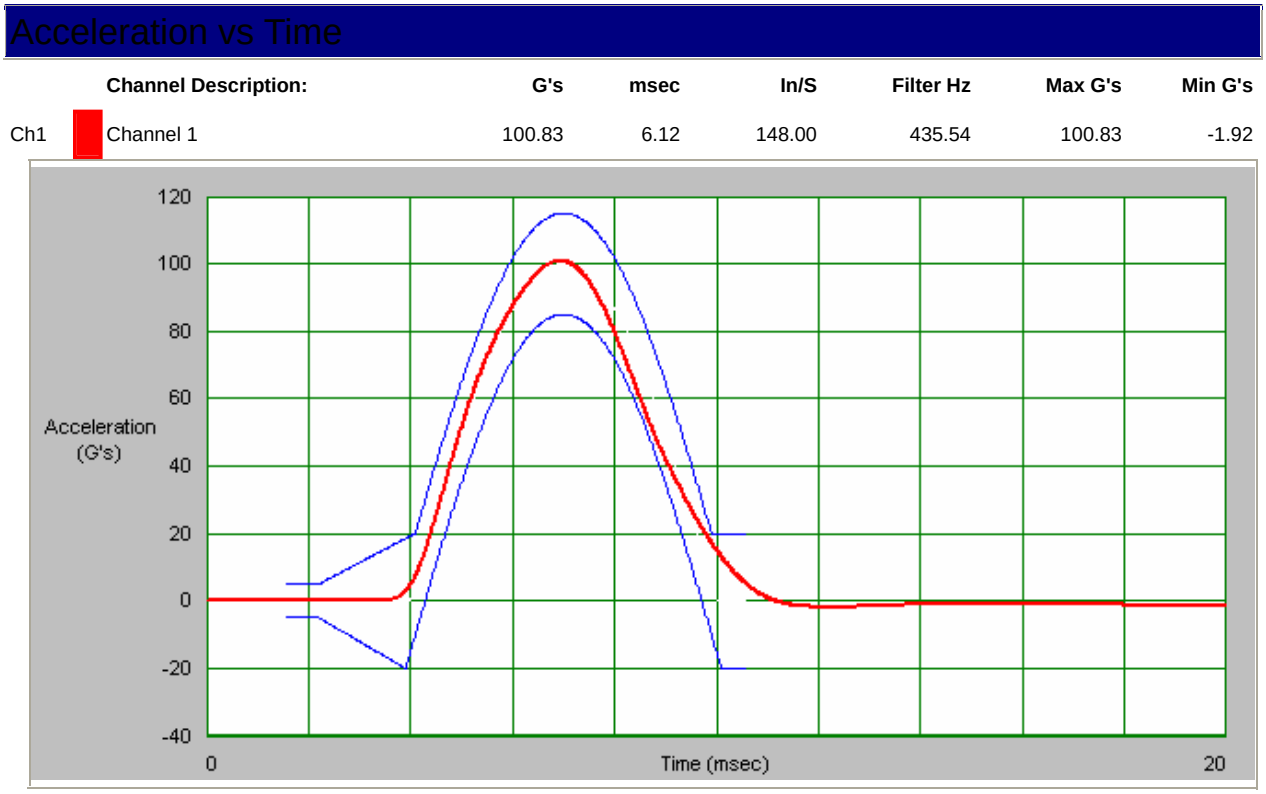
Axis -Z

Test Curve:



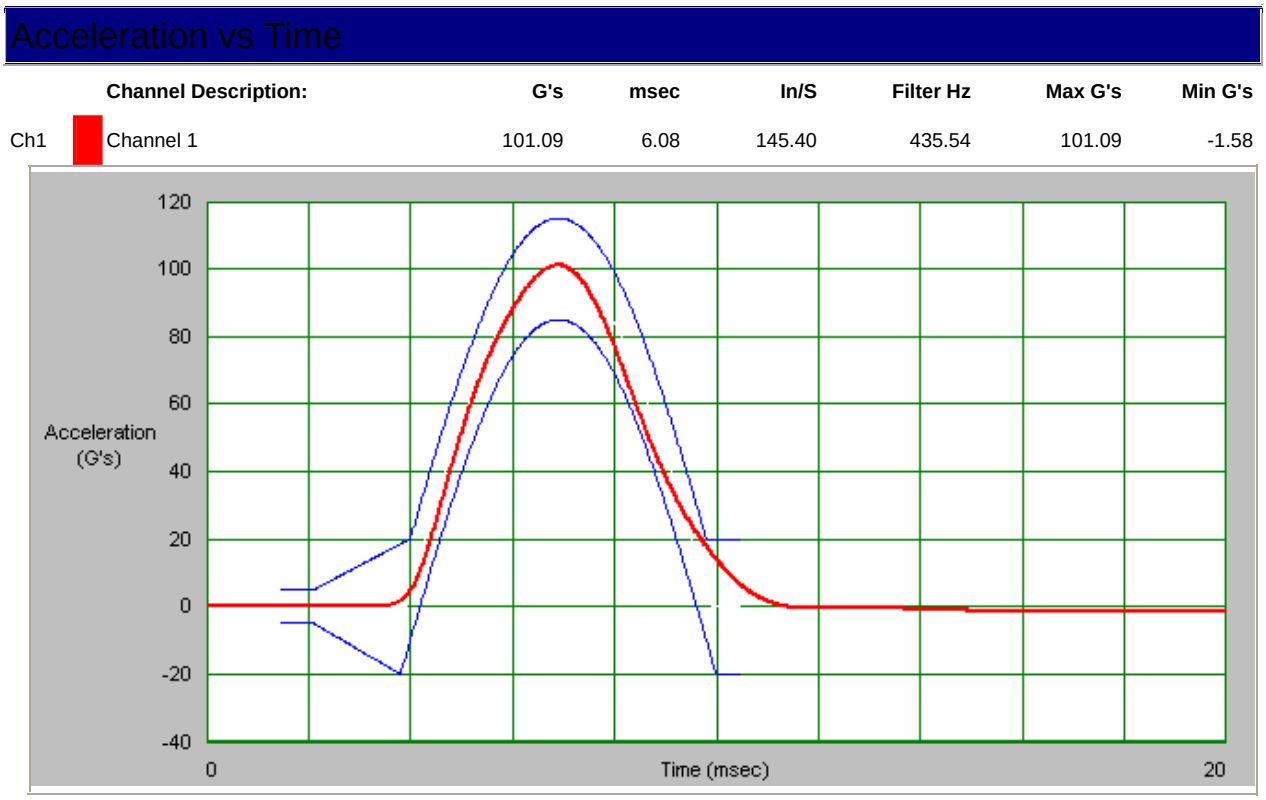
Axis +X

Test Curve:



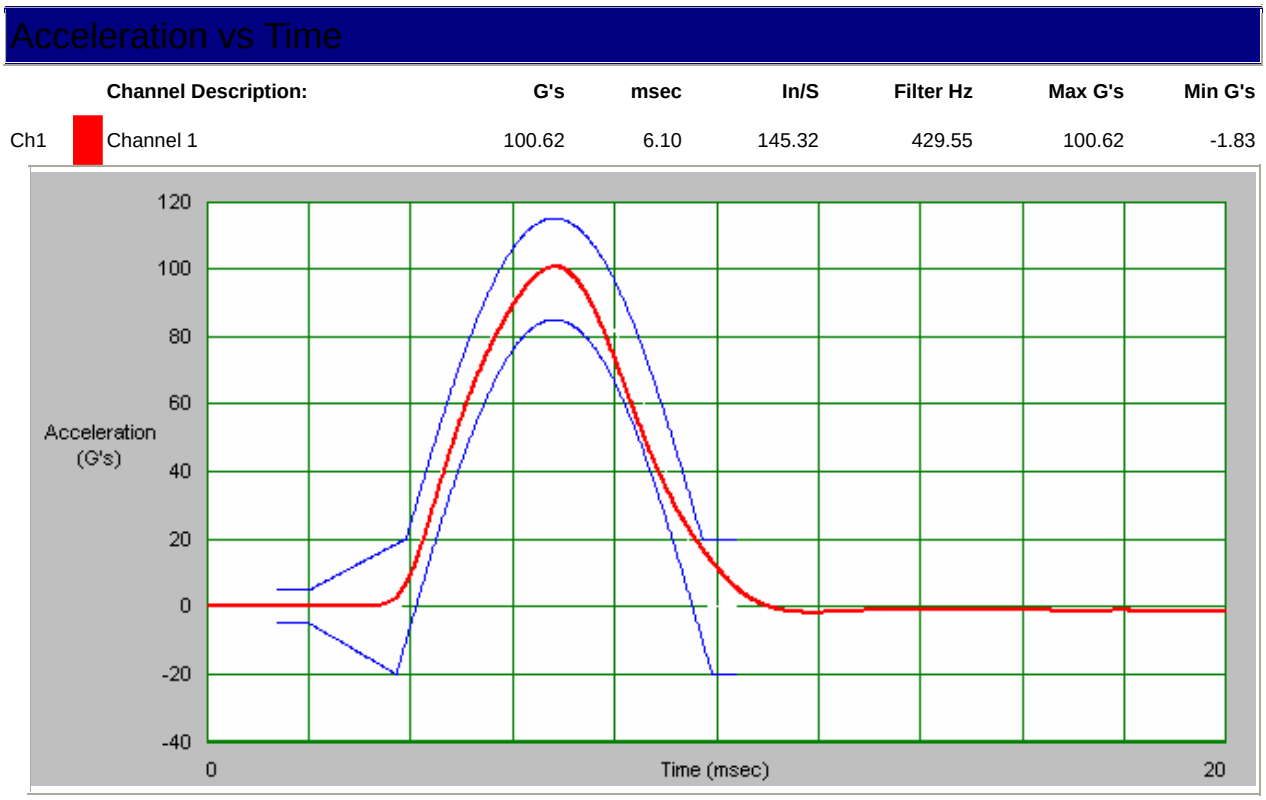
Axis -X

Test Curve:



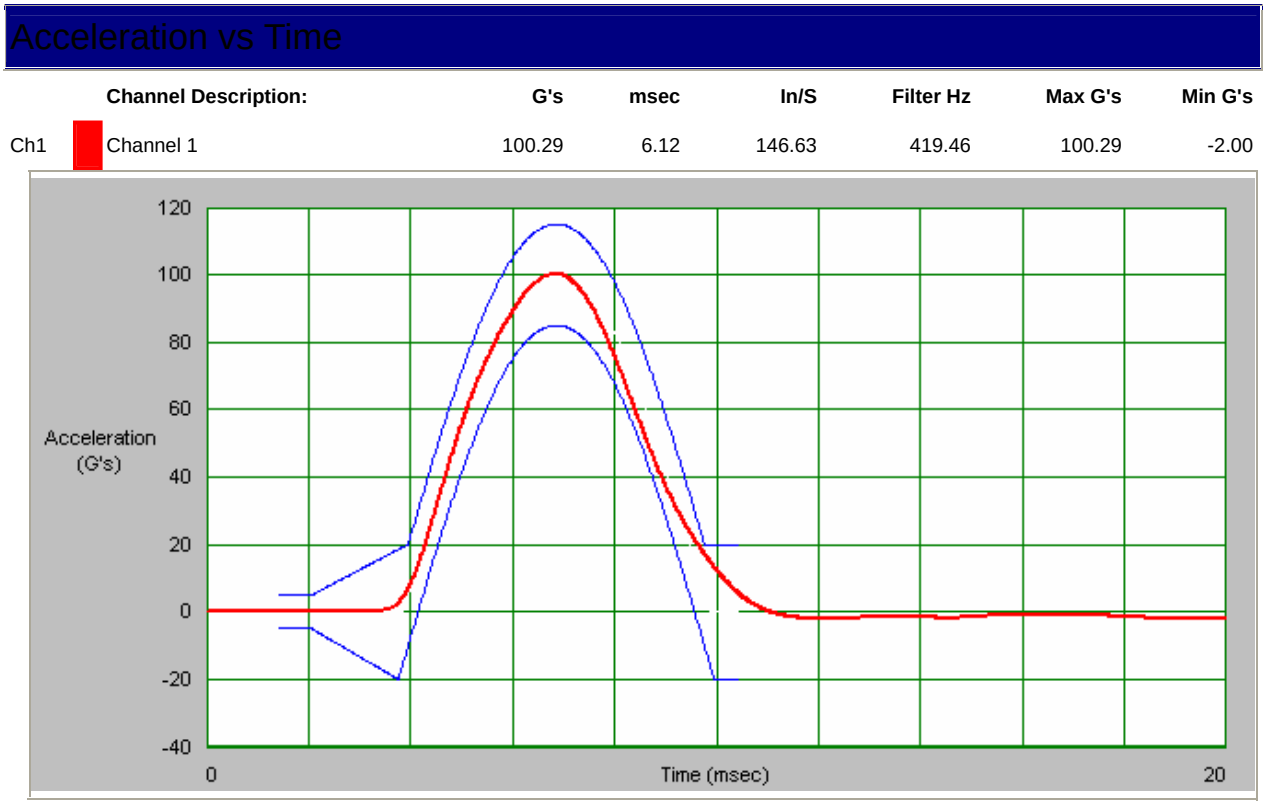
Axis +Y

Test Curve:



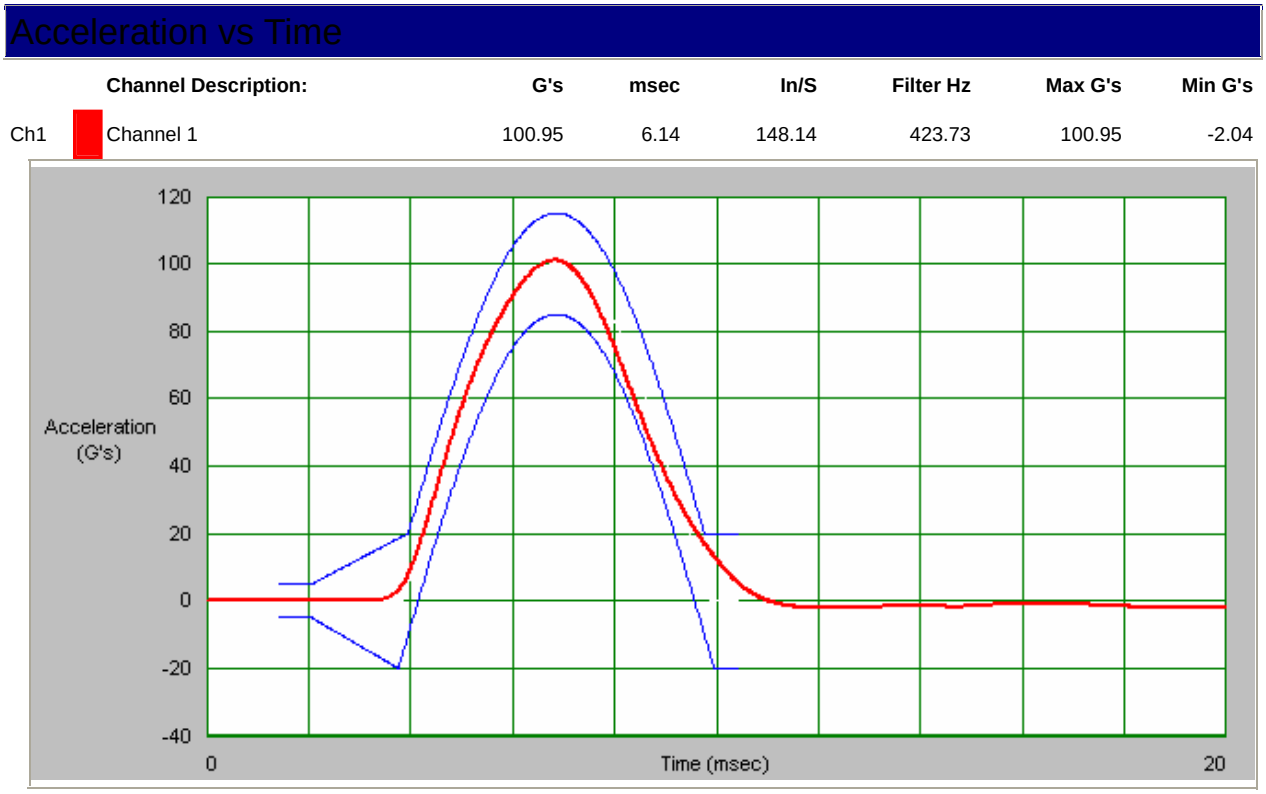
Axis -Y

Test Curve:



Axis +Z

Test Curve:



Axis -Z

Test Seq. (c)

Test Item 3: Low Level Contact Resistance (LLCR)

(1) Test Equipment:

Sample No.	Model	Serial No	Valid Date to
Milliohmmeter	4338B	BTTEELSZ20034	Feb. 13, 2011

(2) Environmental Conditions:

Temperature: 25℃ Humidity: 51%RH

(3) Reference Standard: EIA-364-23B-2000

(4) Tested Sample: 015~022

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

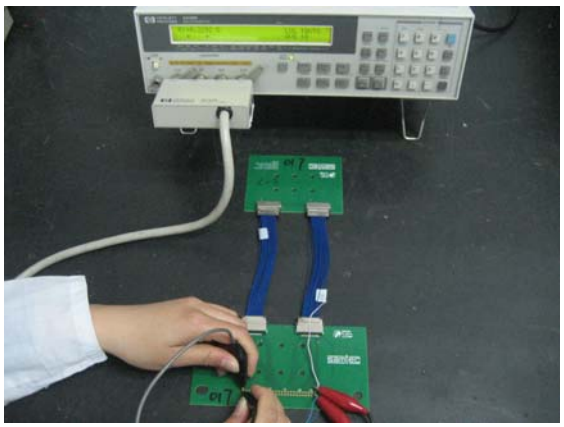
---Test Current: 10 milliamps max

---△R≤15 mΩ

--- Measure and record the Low Level Contact Resistance

Test Results: Please see the appendix from page 35 to page 42.

Test Photo:



Test Item 4: Random Vibration Test

(1) Test Equipment:

Name	Model	Serial No.	Valid Date to
Vibration Test System	LDS V850-440-LPT 750	ATTEELSZ20020	Feb. 19, 2010
Vibration Test System	EM-400F2K-30N80	BTTEELSZ20011	May. 25, 2010

(2) Environmental Conditions:

Temperature: 25℃ Humidity: 54%RH

(3) Reference Standard: EIA-364-28E-2006

(4) Tested Samples: 015~022

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

Frequency (Hz)	PSD (g^2/ Hz)	Slope (dB/oct)
50	/	+6
100-1000	0.04	/
2000	/	-6

---Acceleration: 7.56 Grms

---Direction: Axis X, Y, Z

---Test duration: 2 hours/axis

(6) Acceptance criteria:

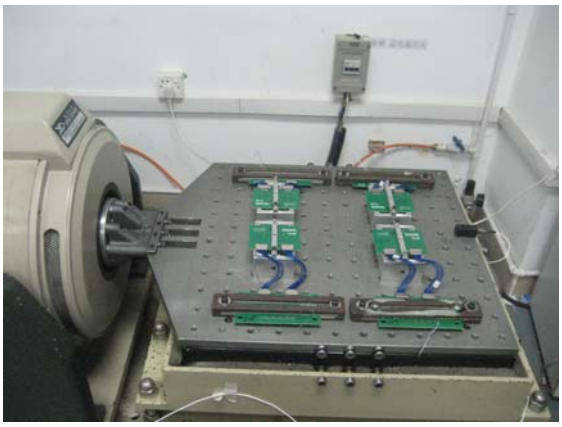
---There shall be no evidence of physical damage to the tested samples.

(7) Note:

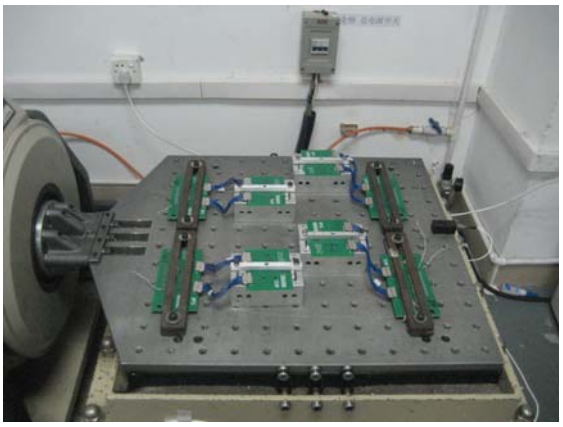
---The samples are divided into 2 groups (Group 1: 015~018 and Group 2: 019~022) for the test.

Test Results: There was no physical damage to the tested samples after the test.

Test Photos:



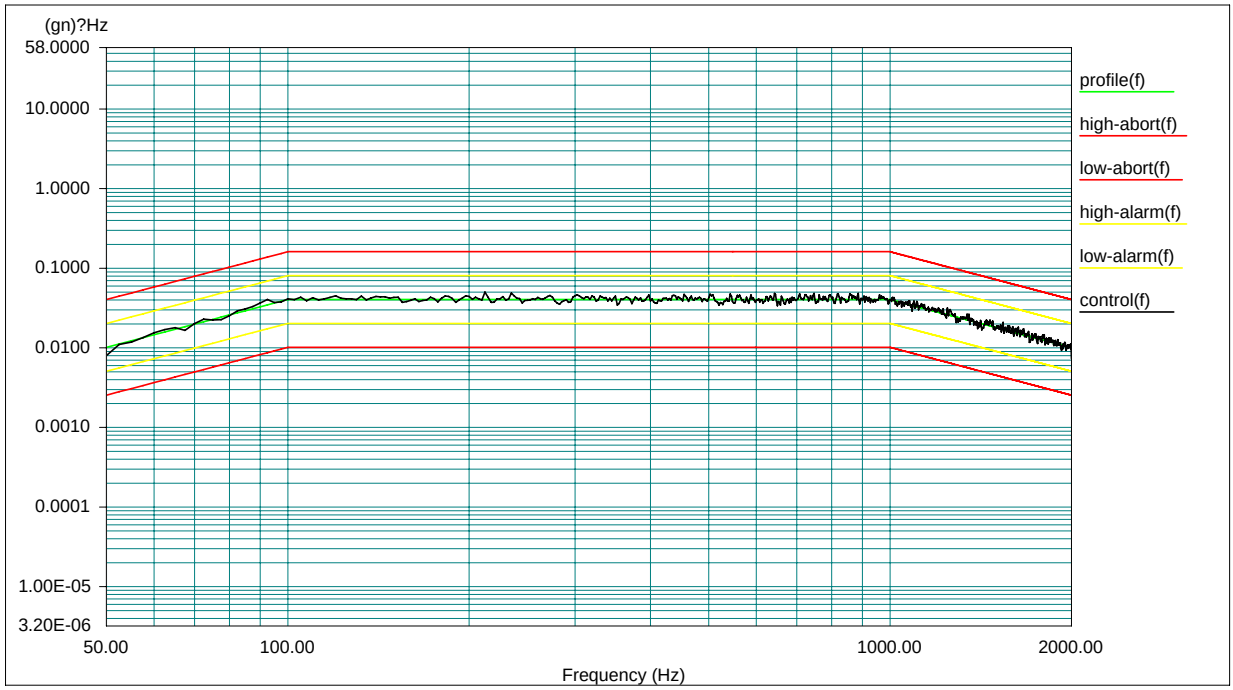
Axis X



Axis Y

Axis Z

Test Curve:



Level: 100 % Control RMS: 7.848115 gn Full Level Elapsed Time: 02:00:00 Lines: 800
Frame Time: 0.400000 Seconds Demand RMS: 7.564701 gn Remaining Time: 00:00:00
DOF: 154 dF: 2.500000 Hz
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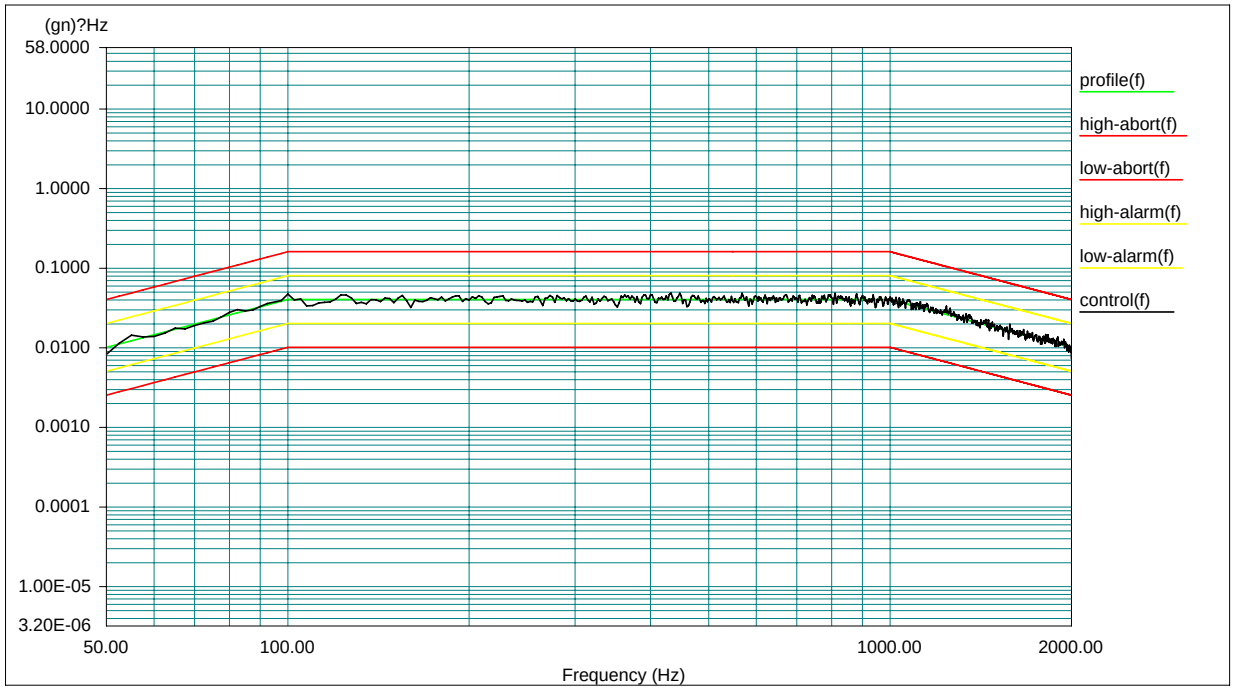
Report created at 09:58:44 PM, Saturday, March 20, 2010

Axis X

Test Curve:



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Frame Time: 0.400000 Seconds Demand RMS: 7.564701 gn Remaining Time: 00:00:00
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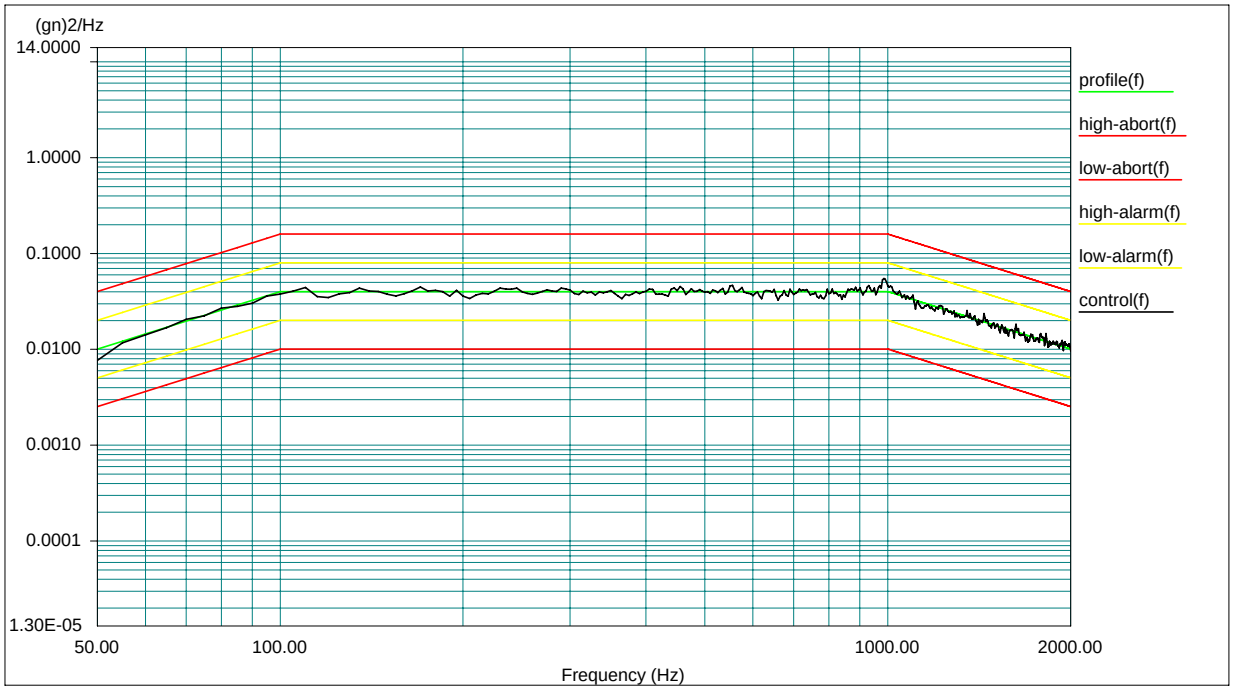
Axis Y

Test Curve:



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Frame Time: 0.200000 Seconds Demand RMS: 7.565556 gn Remaining Time: 00:00:00
DOF: 154 dF: 5.000000 Hz
Data saved at 04:06:39 PM, Sunday, March 27, 2010
Report created at 04:06:42 PM, Sunday, March 27, 2010

Axis Z

Test Seq. (c):

Test Item 5: Low Level Contact Resistance (LLCR)

(1) Test Equipment:

Sample No.	Model	Serial No	Valid Date to
Milliohmmeter	4338B	BTTEELSZ20034	Feb. 13, 2011

(2) Environmental Conditions:

Temperature: 25℃ Humidity: 51%RH

(3) Reference Standard: EIA-364-23B-2000

(4) Tested Sample: 015~022

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

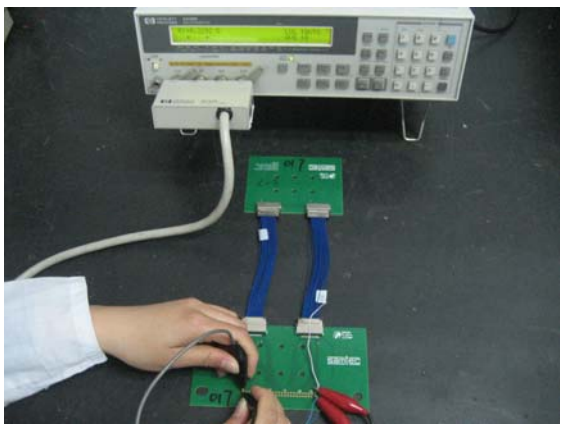
---Test Current: 10 milliamps max

---△R≤15 mΩ

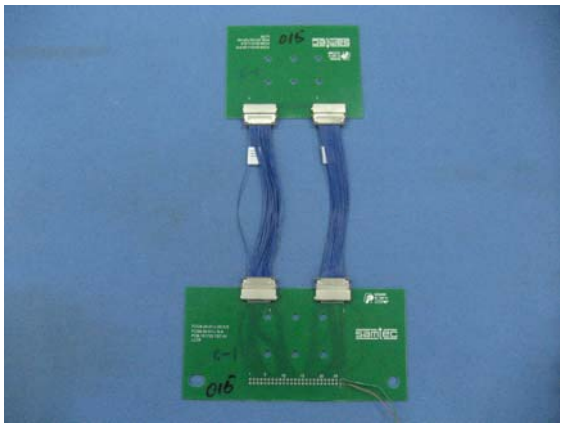
--- Measure and record the Low Level Contact Resistance

Test Results: Please see the appendix from page 35 to page 42.

Test Photo:



Sample Photo after Testing Seq. (c):



Test Seq. (d):

Test Item 1: Mechanical shock test

(1) Test Equipment:

Name	Model	Serial No	Valid Date to
Mechanical Shock Test System	DP-1200-45	BTTEELSZ20033	May. 25, 2010
Instantaneous circuit tester	NM11A	BTTEELSZ20016	Nov. 05, 2010

(2) Environmental Conditions:

Temperature: 24℃ Humidity: 52%RH

(3) Reference Standard: EIA-364-27B-1996

(4) Tested Sample: 023~026

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

---Wave form: Half-sine

---Acceleration: 100 g_n

--- Pulse duration: 6 ms

---Direction: Axis ±X, ±Y, ±Z

---Number of shocks: 3 shocks /axis, 18 times in total

---Monitor the discontinuity duration of samples during the test

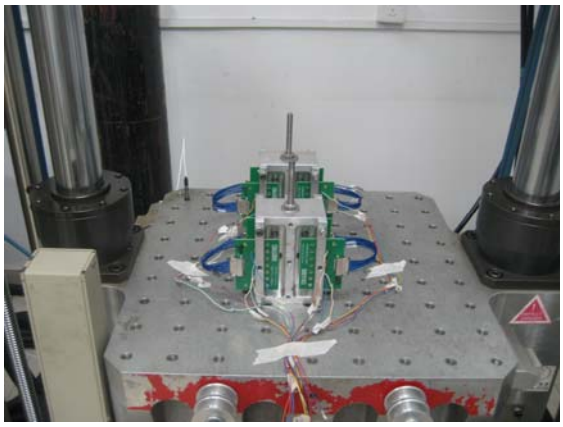
(6) Acceptance criteria:

---There shall be no evidence of physical damage to the tested samples;

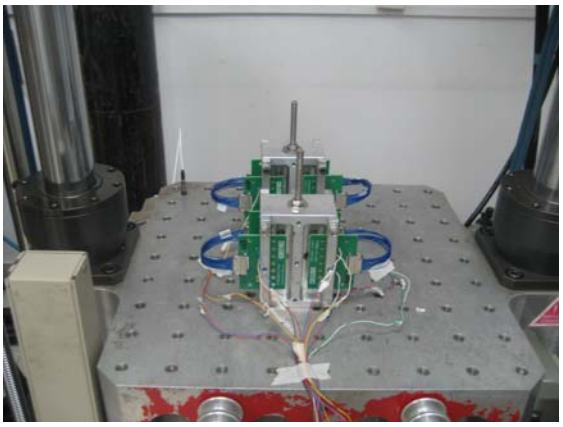
---There shall be no low microsecond event detected greater than 0.1 microsecond.

Test Results: There was no evidence of physical damage to the tested samples, there was no low microsecond event detected greater than 0.1 microsecond. Other characteristics should be evaluated by the client.

Test Photos:

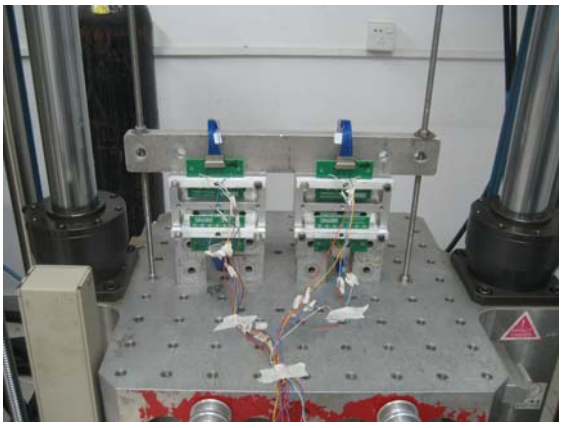


Axis +X

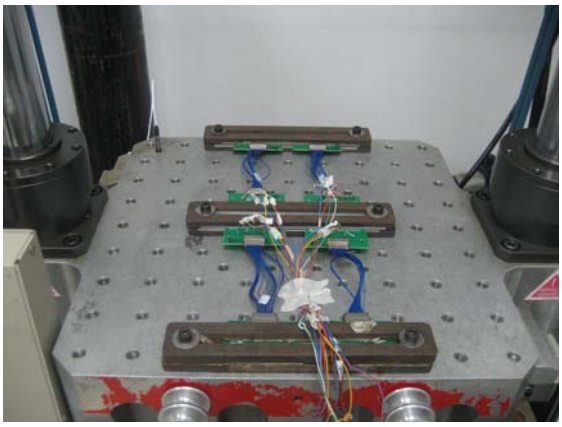


Axis -X

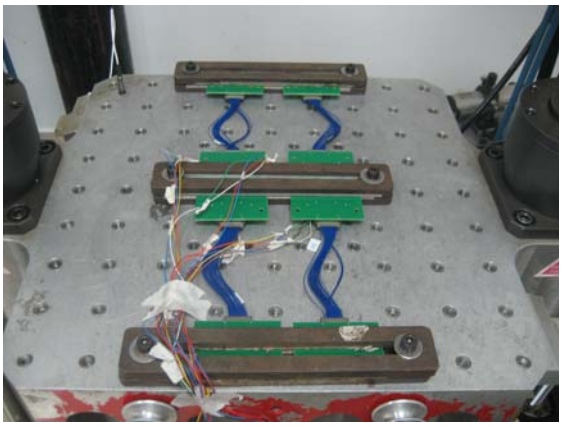
Axis +Y



Axis -Y



Axis +Z

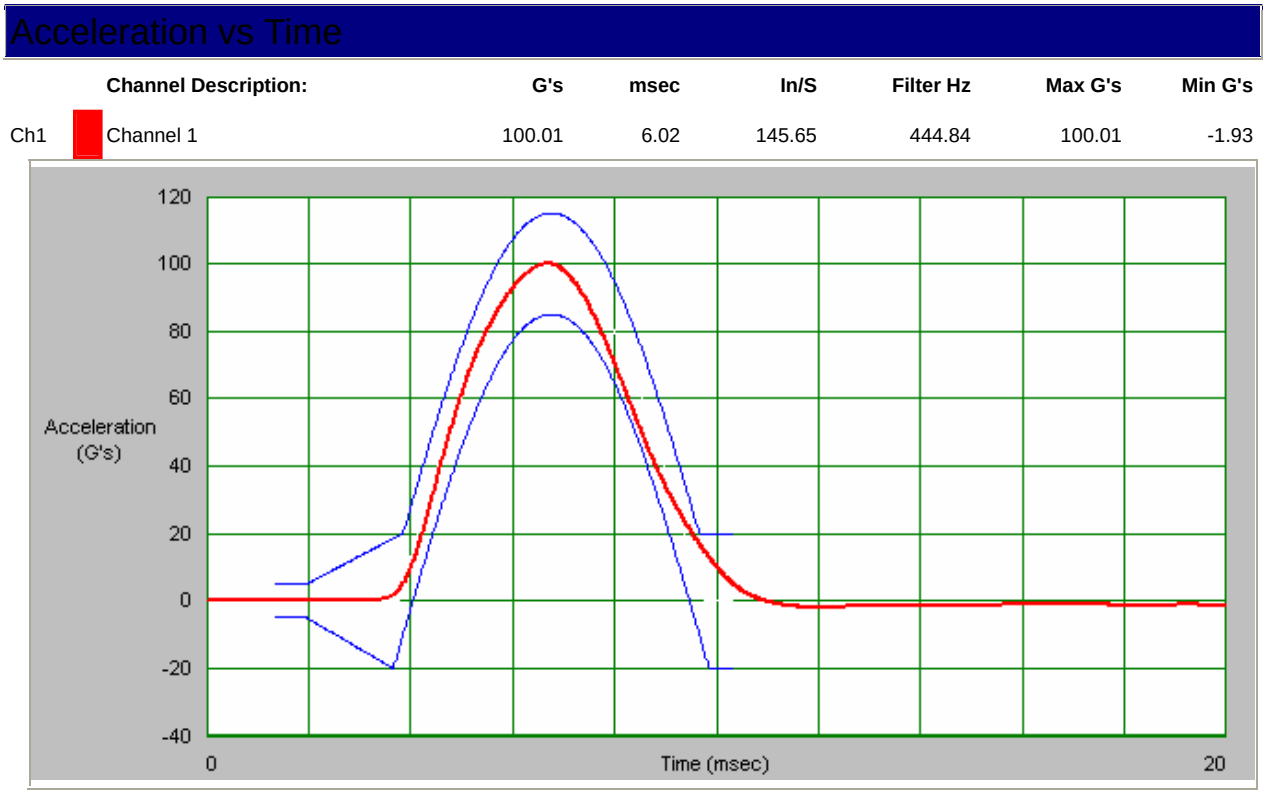


Axis -Z

Test Photo:

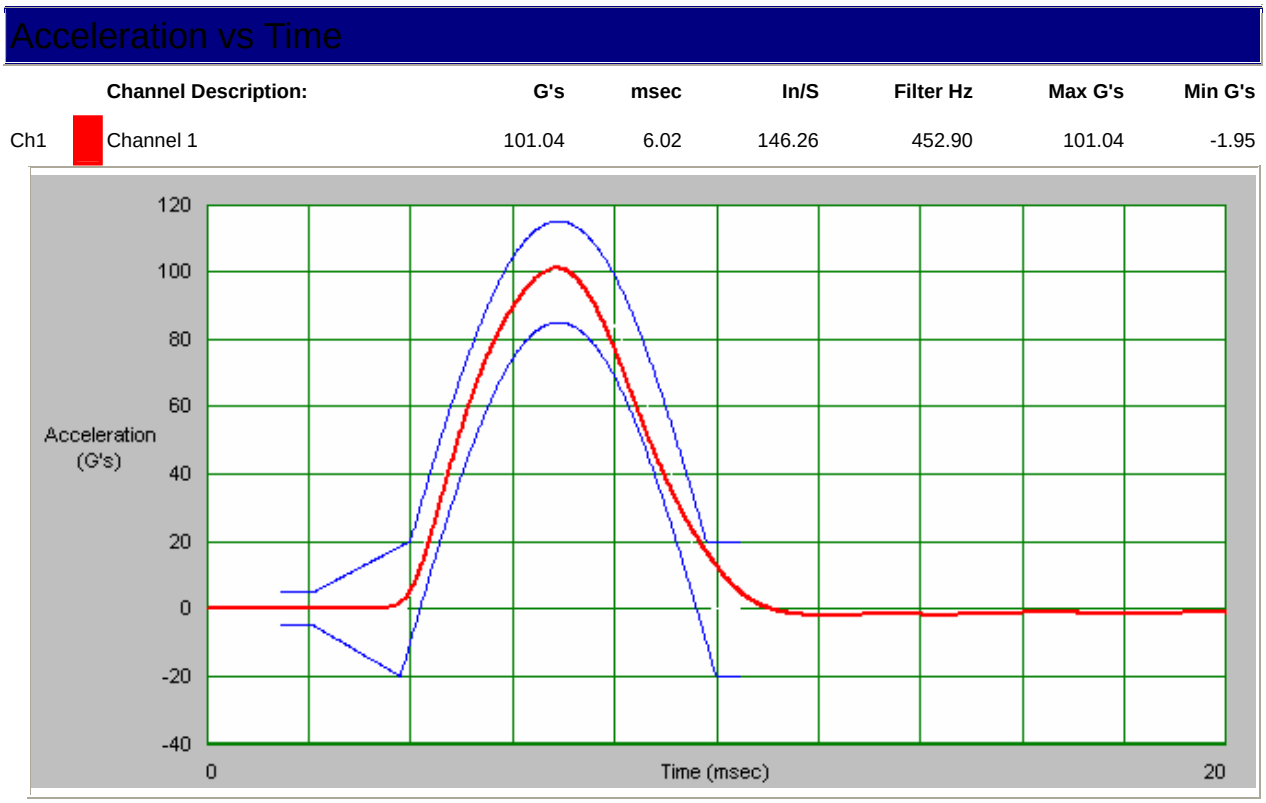
Monitor during the test

Test Curve:



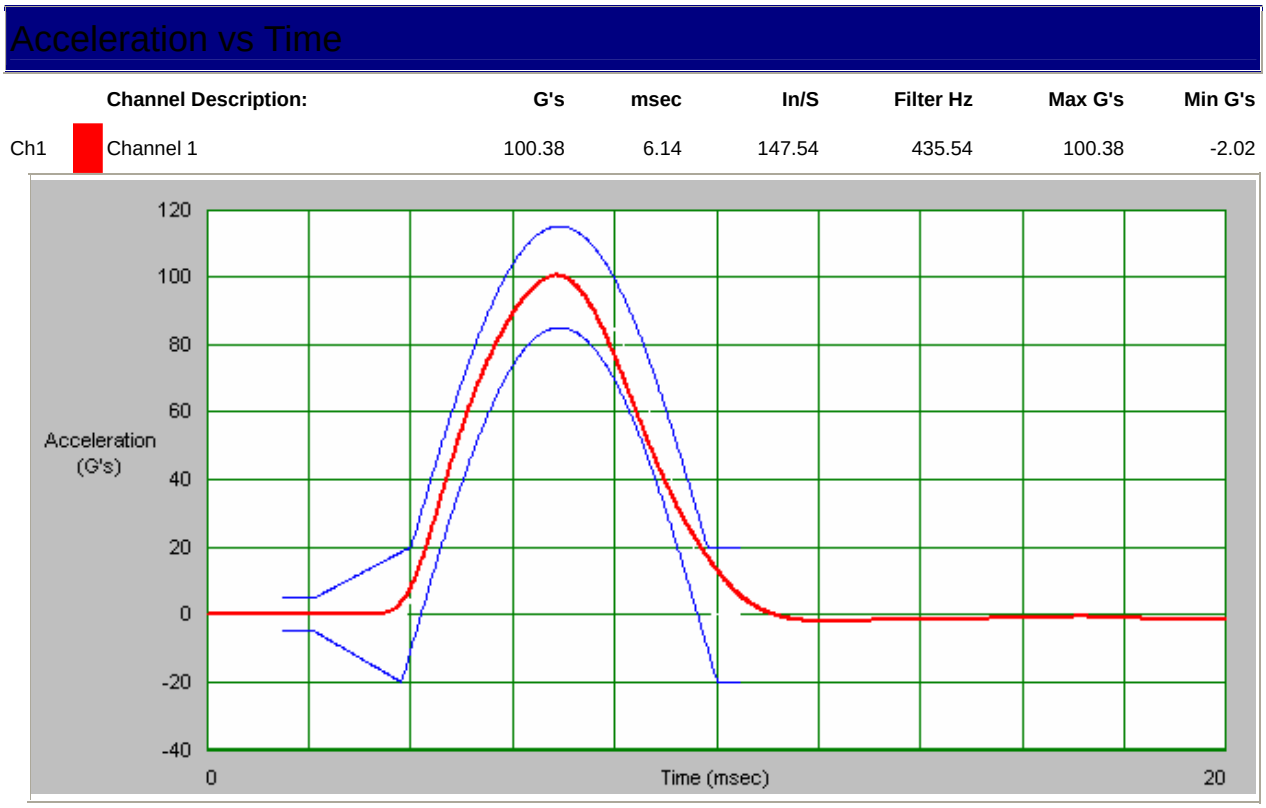
Axis +X

Test Curve:



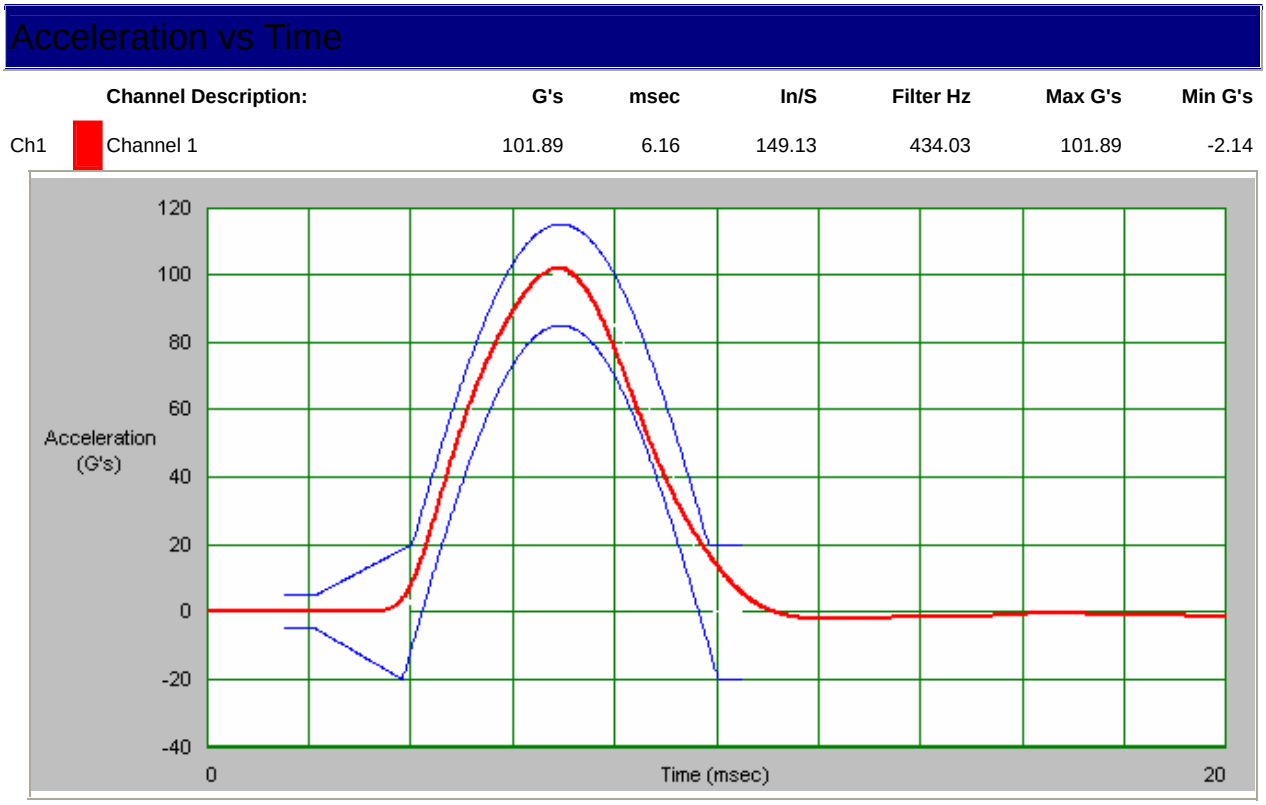
Axis -X

Test Curve:



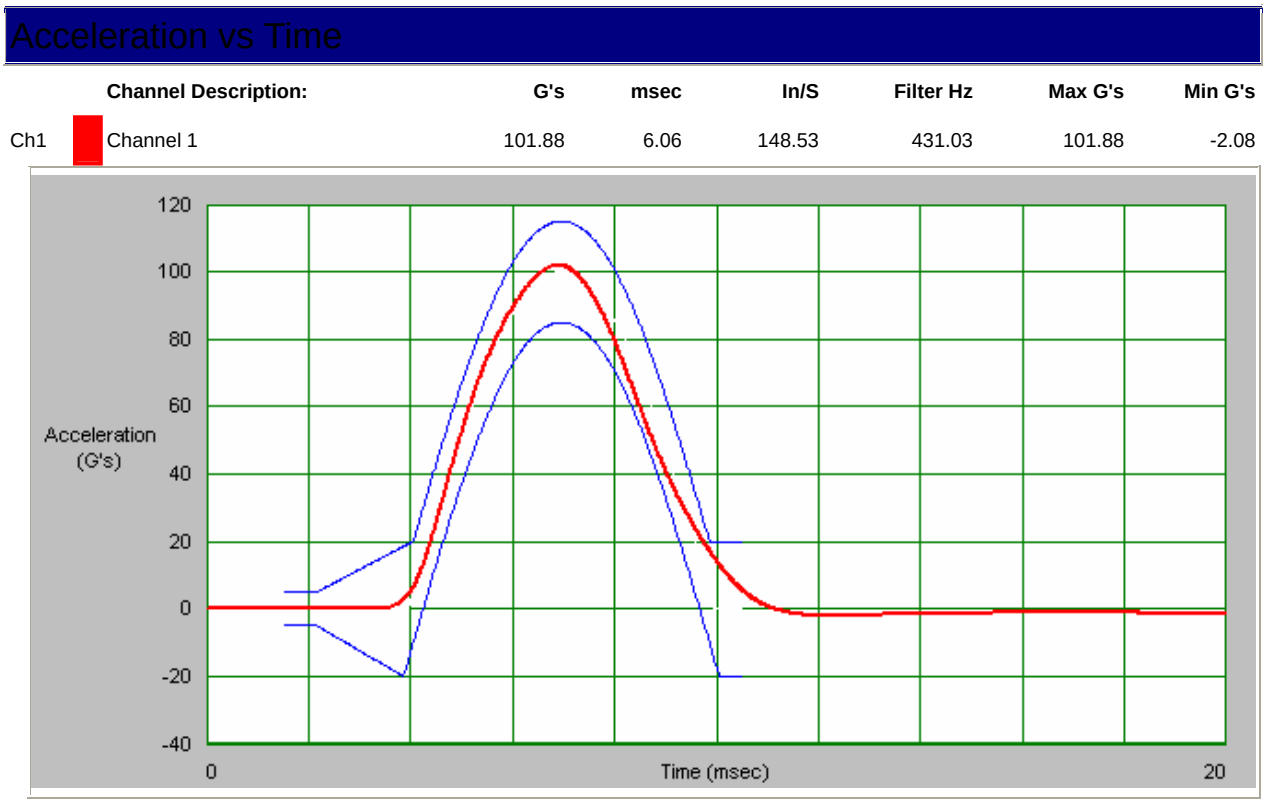
Axis +Y

Test Curve:



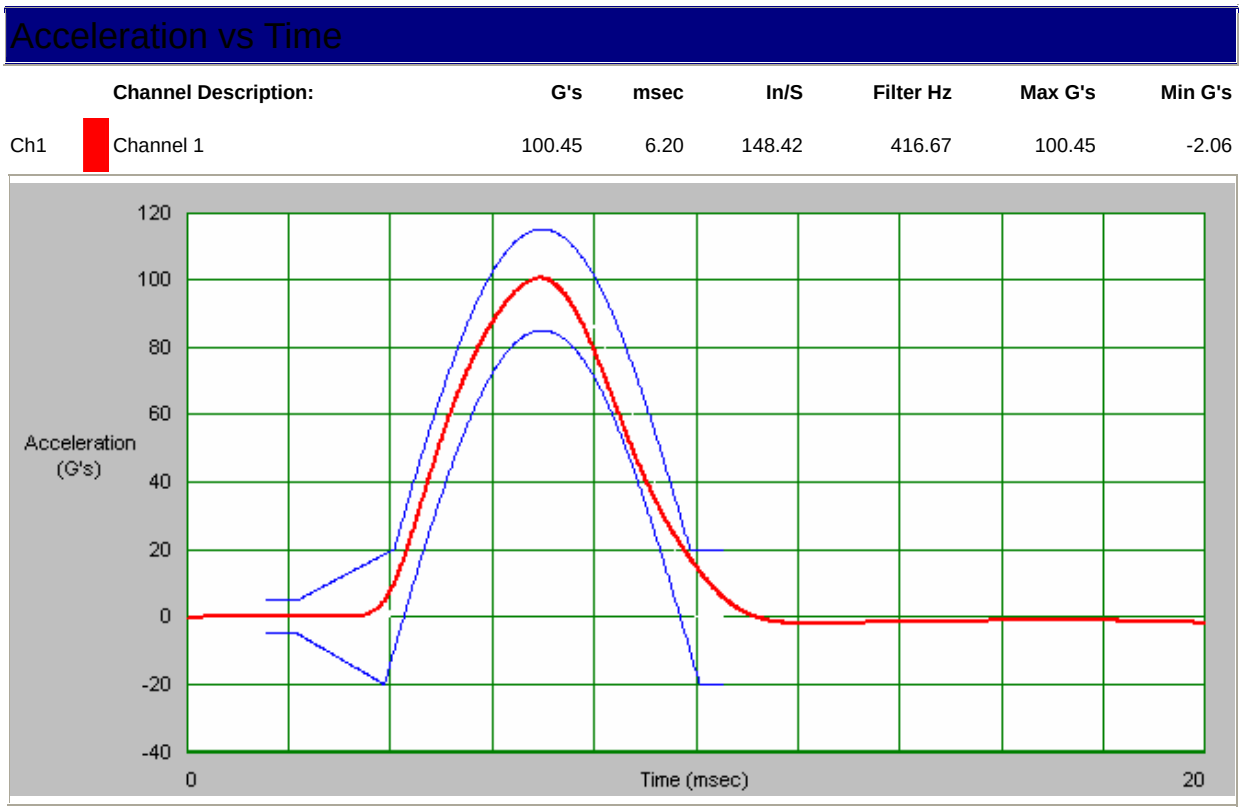
Axis -Y

Test Curve:



Axis +Z

Test Curve:



Axis -Z

Test Item 2: Random Vibration Test

(1) Test Equipment:

Name	Model	Serial No.	Valid Date to
Vibration Test System	EM-400F2K-30N80	BTTEELSZ20011	May. 25, 2010
Vibration Test System	LDS V850-440-LPT 750	ATTEELSZ00020	Mar. 18, 2011
Instantaneous circuit tester	NM11A	BTTEELSZ20016	Nov. 05, 2010

(2) Environmental Conditions:

Temperature: 25℃ Humidity: 54%RH

(3) Reference Standard: EIA-364-28E-2006

(4) Tested Samples: 023~026

(5) Test Condition:

The test performed in accordance to the criteria listed above, and under the conditions as below:

Frequency(Hz)	PSD (g^2/ Hz)	Slope (dB/oct)
50	/	+6
100-1000	0.04	/
2000	/	-6

---Acceleration: 7.56 Grms

---Direction: Axis X, Y, Z

---Test duration: 2 hours/axis

---Monitor the discontinuity duration of samples during the test

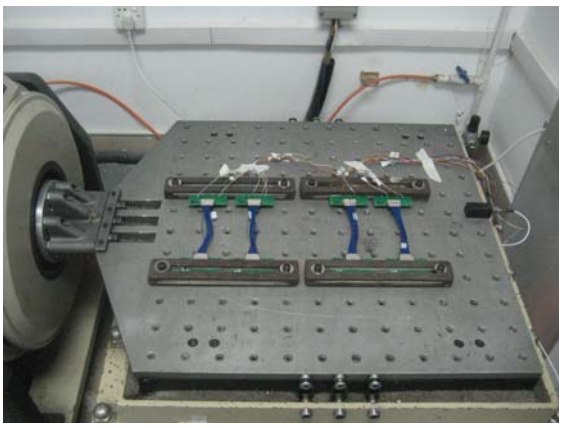
(6) Acceptance criteria:

---There shall be no evidence of physical damage to the tested samples;

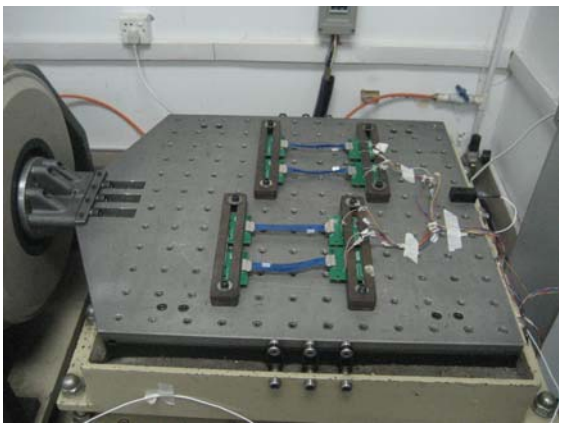
---There shall be no low microsecond event detected greater than 0.1 microsecond.

Test Results: There was no evidence of physical damage to the tested samples, there was no low microsecond event detected greater than 0.1 microsecond. Other characteristics should be evaluated by the client.

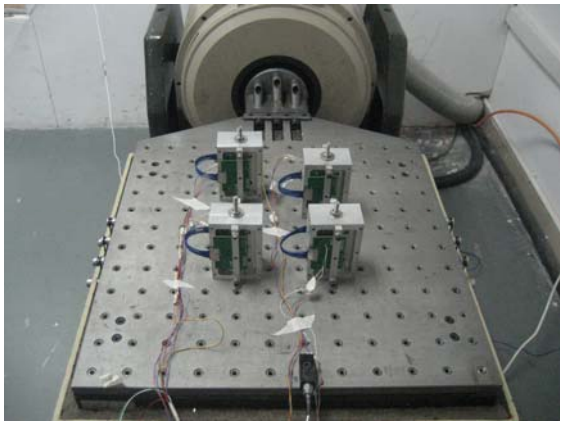
Test Photos:



Axis X



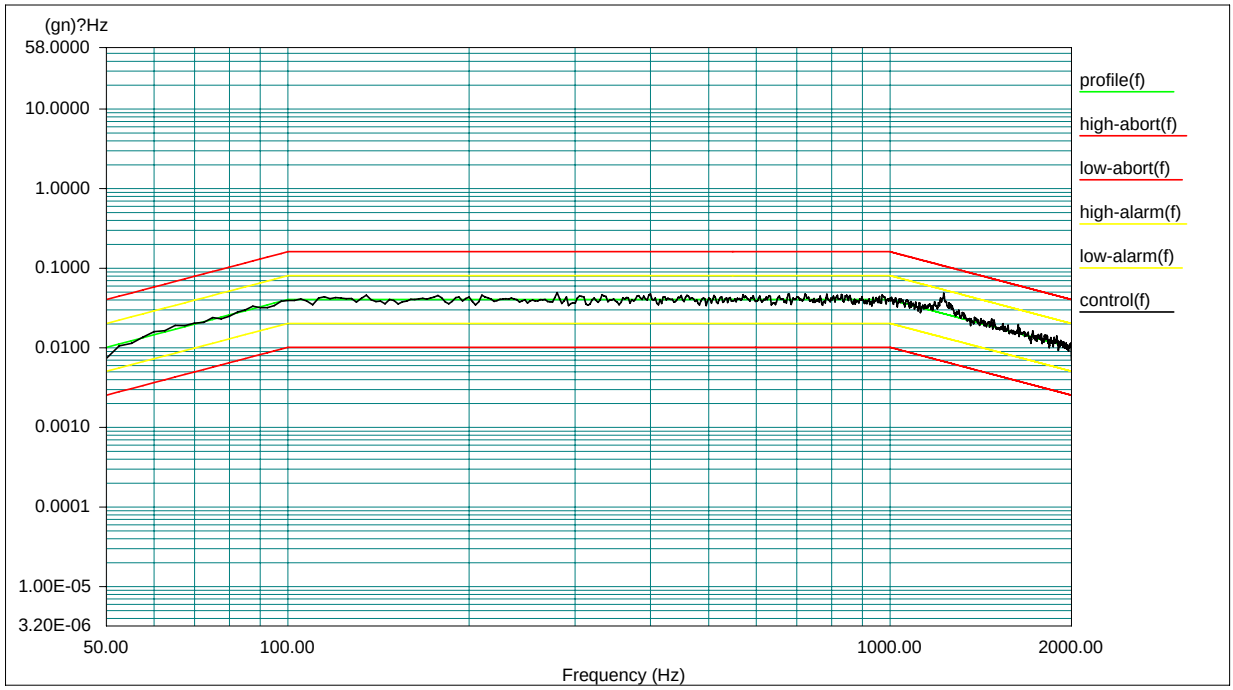
Axis Y



Axis Z

Monitor during the test

Test Curve:



Level: 100 % Control RMS: 7.748030 gn Full Level Elapsed Time: 02:00:02 Lines: 800
Frame Time: 0.400000 Seconds Demand RMS: 7.564701 gn Remaining Time: 00:00:00
DOF: 154 dF: 2.500000 Hz
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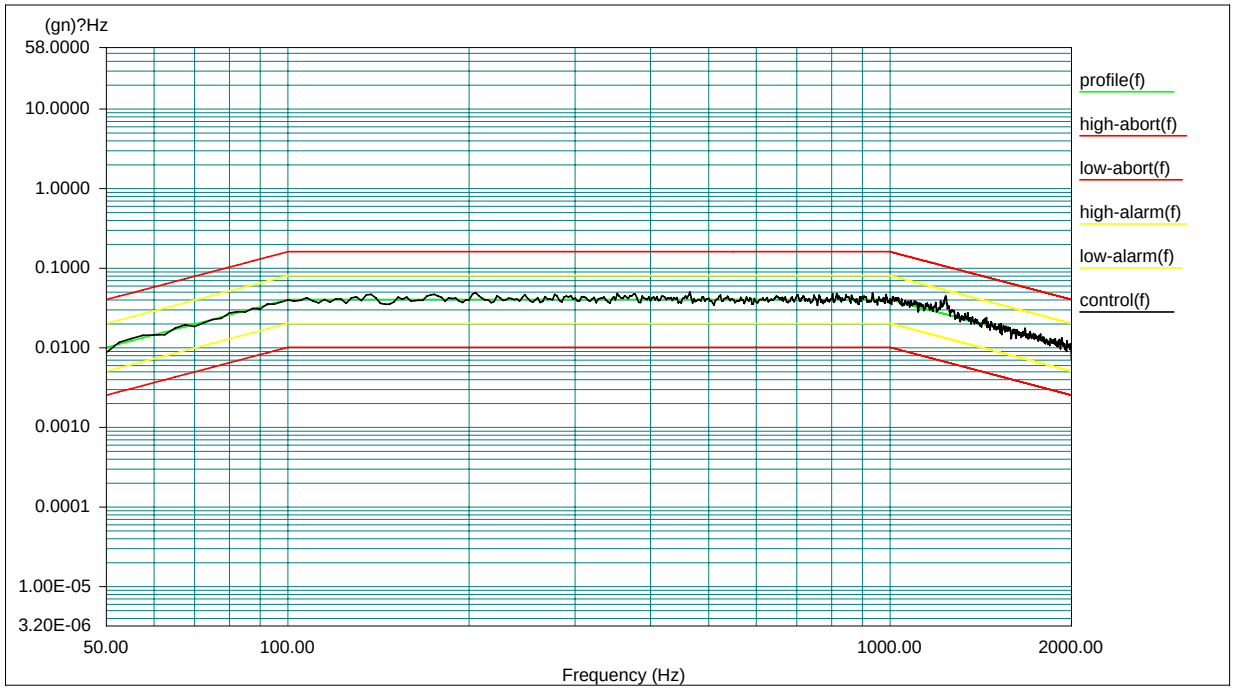
Report created at 12:03:01 PM, Saturday, March 20, 2010

Axis X

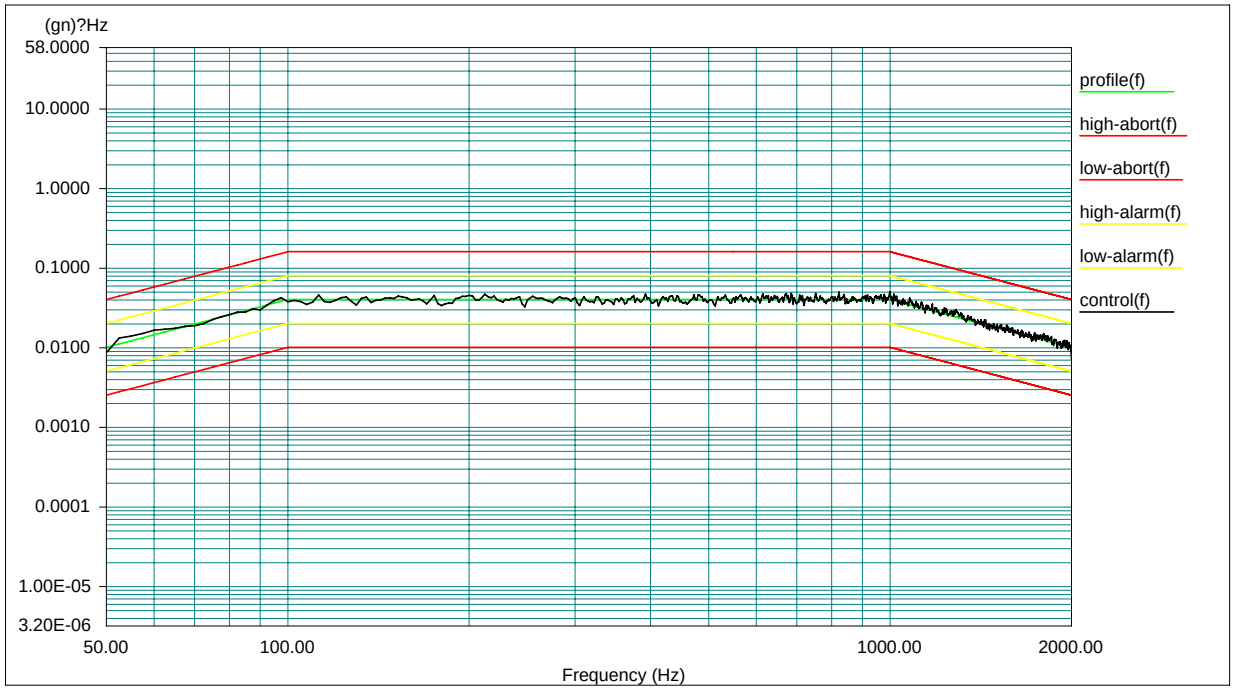
Test Curve:



Level: 100 % Control RMS: 7.751250 gn Full Level Elapsed Time: 02:00:00 Lines: 800
Frame Time: 0.400000 Seconds Demand RMS: 7.564701 gn Remaining Time: 00:00:00
DOF: 154 dF: 2.500000 Hz
Data saved at 02:17:35 PM, Saturday, March 20, 2010
Report created at 02:17:36 PM, Saturday, March 20, 2010

Axis Y

Test Curve:



Level: 100 % Control RMS: 7.769923 gn Full Level Elapsed Time: 02:00:04 Lines: 800
Frame Time: 0.400000 Seconds Demand RMS: 7.564701 gn Remaining Time: 00:00:00
DOF: 154 dF: 2.500000 Hz
Data saved at 07:35:15 PM, Saturday, March 20, 2010
Report created at 07:35:16 PM, Saturday, March 20, 2010

Axis Z

Sample Photo after Testing Seq. (d):

Appendix: Data of the resistance after Testing Seq. (c)

Sample No.	Customer No.	Pin No.	LLCR（mΩ）				
			Initial	After shock test	ΔR1	After vibration test	ΔR2
015	C-1	pin 1	228.2	227.1	-1.1	224.5	-3.7
		pin 2	226.2	224.9	-1.3	225.8	-0.4
		pin 3	226.5	226.3	-0.2	225.4	-1.1
		pin 4	226.9	224.4	-2.5	224.6	-2.3
		pin 5	226.4	224.9	-1.5	228.7	2.3
		pin 6	227.0	225.1	-1.9	226.8	-0.2
		pin 7	229.8	226.3	-3.5	232.9	3.1
		pin 8	227.0	224.9	-2.1	221.6	-5.4
		pin 9	222.4	220.4	-2.0	227.5	5.1
		pin 10	228.3	226.3	-2.0	224.4	-3.9
		pin 11	231.1	230.1	-1	226.3	-4.8
		pin 12	228.0	226.3	-1.7	225.4	-2.6
		pin 13	230.6	229.2	-1.4	220.3	-10.3
		pin 14	226.7	224.8	-1.9	229.5	2.8
		pin 15	228.9	227.8	-1.1	228.7	-0.2
		pin 16	228.1	226.2	-1.9	225.7	-2.4
		pin 17	226.4	225.7	-0.7	226.6	0.2
		pin 18	226.4	224.7	-1.7	223.9	-2.5
		pin 19	223.2	221.7	-1.5	222.6	-0.6
		pin 20	225.7	223.9	-1.8	225.7	0.0
		pin 21	227.4	225.6	-1.8	227.3	-0.1
		pin 22	222.8	221.7	-1.1	224.5	1.7
		pin 23	228.3	226.4	-1.9	228.7	0.4
		pin 24	225.5	223.5	-2.0	224.7	-0.8
ΔR1=R(after shock)- R(initial)							
ΔR2=R(after vibration)- R(initial)							

Appendix (Cont.): Data of the resistance after Testing Seq. (c)

Sample No.	Customer No.	Pin No.	LLCR（mΩ）				
			Initial	After shock test	ΔR1	After vibration test	ΔR2
016	C-2	pin 1	230.0	228.4	-1.6	226.3	-3.7
		pin 2	230.8	219.2	-11.6	221.8	-9.0
		pin 3	224.1	221.9	-2.2	222.9	-1.2
		pin 4	220.4	218.8	-1.6	220.8	0.4
		pin 5	229.5	228.0	-1.5	230.6	1.1
		pin 6	226.5	224.4	-2.1	228.7	2.2
		pin 7	224.2	222.3	-1.9	222.7	-1.5
		pin 8	222.3	220.7	-1.6	221.0	-1.3
		pin 9	223.9	222.2	-1.7	223.6	-0.3
		pin 10	226.9	224.7	-2.2	227.2	0.3
		pin 11	223.8	221.6	-2.2	223.8	0.0
		pin 12	230.8	228.9	-1.9	231.4	0.6
		pin 13	225.3	224.0	-1.3	226.7	1.4
		pin 14	222.4	220.9	-1.5	223.0	0.6
		pin 15	248.4	230.5	-17.9	221.5	-26.9
		pin 16	226.2	225.1	-1.1	227.4	1.2
		pin 17	225.7	224.2	-1.5	224.7	-1.0
		pin 18	223.9	222.3	-1.6	224.9	1.0
		pin 19	227.8	227.4	-0.4	228.5	0.7
		pin 20	226.0	223.8	-2.2	227.8	1.8
		pin 21	230.5	227.9	-2.6	229.6	-0.9
		pin 22	223.6	222.6	-1.0	224.3	0.7
		pin 23	218.9	217.6	-1.3	220.3	1.4
		pin 24	227.3	226.5	-0.8	228.7	1.4
ΔR1=R(after shock)- R(initial)							
ΔR2=R(after vibration)- R(initial)							
Note: Pin 15 of sample 016 are excluded due to the initial reading is high.							

Appendix (Cont.): Data of the resistance after Testing Seq. (c)

Sample No.	Customer No.	Pin No.	LLCR（mΩ）				
			Initial	After shock test	ΔR1	After vibration test	ΔR2
017	C-3	pin 1	227.9	227.4	-0.5	229.2	1.3
		pin 2	225.6	223.7	-1.9	224.9	-0.7
		pin 3	227.0	226.9	-0.1	227.8	0.8
		pin 4	225.3	223.6	-1.7	224.9	-0.4
		pin 5	226.4	224.1	-2.3	225.1	-1.3
		pin 6	226.4	224.7	-1.7	225.9	-0.5
		pin 7	228.0	226.3	-1.7	228.7	0.7
		pin 8	225.1	223.4	-1.7	222.7	-2.4
		pin 9	222.5	221.9	-0.6	221.8	-0.7
		pin 10	222.8	222.2	-0.6	222.7	-0.1
		pin 11	231.7	231.9	0.2	232.2	0.5
		pin 12	228.4	225.9	-2.5	227.1	-1.3
		pin 13	230.1	228.5	-1.6	227.0	-3.1
		pin 14	228.3	226.8	-1.5	227.4	-0.9
		pin 15	224.7	226.4	1.7	224.7	0.0
		pin 16	228.3	227.3	-1.0	227.5	-0.8
		pin 17	221.7	222.7	1.0	221.2	-0.5
		pin 18	222.5	221.2	-1.3	221.8	-0.7
		pin 19	226.9	228.1	1.2	226.1	-0.8
		pin 20	227.1	225.7	-1.4	227.1	0.0
		pin 21	225.3	224.8	-0.5	225.1	-0.2
		pin 22	229.4	225.2	-4.2	223.5	-5.9
		pin 23	221.4	220.4	-1.0	220.1	-1.3
		pin 24	226.2	224.5	-1.7	225.9	-0.3
ΔR1=R(after shock)- R(initial)							
ΔR2=R(after vibration)- R(initial)							

Appendix (Cont.): Data of the resistance after Testing Seq. (c)

Sample No.	Customer No.	Pin No.	LLCR（mΩ）				
			Initial	After shock test	ΔR1	After vibration test	ΔR2
018	C-4	pin 1	224.2	225.9	1.7	226.8	2.6
		pin 2	220.3	221.1	0.8	223.1	2.8
		pin 3	226.5	226.3	-0.2	226.9	0.4
		pin 4	227.5	227.1	-0.4	228.8	1.3
		pin 5	226.4	225.8	-0.6	227.3	0.9
		pin 6	227.1	226.2	-0.9	228.0	0.9
		pin 7	226.5	227.3	0.8	228.8	2.3
		pin 8	222.5	224.4	1.9	224.3	1.8
		pin 9	223.5	223.7	0.2	224.8	1.3
		pin 10	224.7	223.8	-0.9	225.3	0.6
		pin 11	227.5	226.6	-0.9	230.3	2.8
		pin 12	230.0	229.1	-0.9	230.5	0.5
		pin 13	222.3	221.9	-0.4	223.2	0.9
		pin 14	223.8	223.9	0.1	224.3	0.5
		pin 15	222.4	222.0	-0.4	223.1	0.7
		pin 16	225.2	224.8	-0.4	225.8	0.6
		pin 17	225.4	225.0	-0.4	225.8	0.4
		pin 18	218.9	218.3	-0.6	219.6	0.7
		pin 19	224.1	223.4	-0.7	222.7	-1.4
		pin 20	222.8	222.4	-0.4	224.1	1.3
		pin 21	220.2	221.0	0.8	222.3	2.1
		pin 22	222.9	222.5	-0.4	223.7	0.8
		pin 23	219.4	219.1	-0.3	220.6	1.2
		pin 24	226.7	227.5	0.8	227.3	0.6
ΔR1=R(after shock)- R(initial)							
ΔR2=R(after vibration)- R(initial)							

Appendix (Cont.): Data of the resistance after Testing Seq. (c)

Sample No.	Customer No.	Pin No.	LLCR（mΩ）				
			Initial	After shock test	ΔR1	After vibration test	ΔR2
019	C-5	pin 1	220.7	218.3	-2.4	221.3	0.6
		pin 2	226.3	224.7	-1.6	227.8	1.5
		pin 3	220.1	218.5	-1.6	221.0	0.9
		pin 4	221.7	220.1	-1.6	224.3	2.6
		pin 5	221.8	220.3	-1.5	226.5	4.7
		pin 6	224.9	223.4	-1.5	228.5	3.6
		pin 7	224.9	223.6	-1.3	221.7	-3.2
		pin 8	220.0	218.7	-1.3	222.3	2.3
		pin 9	220.3	218.5	-1.8	220.8	0.5
		pin 10	220.0	218.4	-1.6	226.2	6.2
		pin 11	223.3	222.7	-0.6	223.7	0.4
		pin 12	223.1	220.6	-2.5	222.4	-0.7
		pin 13	220.9	219.7	-1.2	228.9	8.0
		pin 14	227.1	225.7	-1.4	231.2	4.1
		pin 15	234.2	228.6	-5.6	227.9	-6.3
		pin 16	226.0	224.8	-1.2	227.9	1.9
		pin 17	227.3	225.7	-1.6	229.6	2.3
		pin 18	221.4	220.4	-1.0	223.4	2.0
		pin 19	220.0	219.1	-0.9	219.4	-0.6
		pin 20	224.7	224.9	0.2	225.4	0.7
		pin 21	226.5	225.8	-0.7	226.0	-0.5
		pin 22	223.4	221.6	-1.8	222.3	-1.1
		pin 23	228.0	227.8	-0.2	229.2	1.2
		pin 24	222.9	222.1	-0.8	224.2	1.3
ΔR1=R(after shock)- R(initial)							
ΔR2=R(after vibration)- R(initial)							

Appendix (Cont.): Data of the resistance after Testing Seq. (c)

Sample No.	Customer No.	Pin No.	LLCR（mΩ）				
			Initial	After shock test	ΔR1	After vibration test	ΔR2
020	C-6	pin 1	227.9	227.8	-0.1	229.6	1.7
		pin 2	223.9	222.2	-1.7	224.1	0.2
		pin 3	227.0	224.5	-2.5	225.8	-1.2
		pin 4	223.9	221.5	-2.4	222.7	-1.2
		pin 5	225.1	222.7	-2.4	224.3	-0.8
		pin 6	226.1	224.3	-1.8	226.7	0.6
		pin 7	227.7	227.2	-0.5	228.5	0.8
		pin 8	222.5	221.2	-1.3	221.4	-1.1
		pin 9	219.2	218.4	-0.8	220.1	0.9
		pin 10	223.3	222.7	-0.6	222.4	-0.9
		pin 11	229.7	228.1	-1.6	229.7	0.0
		pin 12	229.4	227.1	-2.3	229.4	0.0
		pin 13	229.8	228.2	-1.6	229.9	0.1
		pin 14	225.6	223.8	-1.8	225.6	0.0
		pin 15	223.5	222.5	-1.0	224.3	0.8
		pin 16	225.0	224.1	-0.9	227.1	2.1
		pin 17	227.9	227.3	-0.6	230.1	2.2
		pin 18	219.5	219.4	-0.1	222.2	2.7
		pin 19	223.6	222.5	-1.1	226.4	2.8
		pin 20	224.6	223.7	-0.9	226.4	1.8
		pin 21	228.9	227.4	-1.5	230.5	1.6
		pin 22	223.7	223.8	0.1	224.1	0.4
		pin 23	219.1	219.2	0.1	220.9	1.8
		pin 24	227.0	228.9	1.9	227.1	0.1
ΔR1=R(after shock)- R(initial)							
ΔR2=R(after vibration)- R(initial)							

Appendix (Cont.): Data of the resistance after Testing Seq. (c)

Sample No.	Customer No.	Pin No.	LLCR（mΩ）				
			Initial	After shock test	ΔR1	After vibration test	ΔR2
021	C-7	pin 1	221.1	218.8	-2.3	219.7	-1.4
		pin 2	225.5	223.7	-1.8	224.9	-0.6
		pin 3	221.3	219.7	-1.6	220.2	-1.1
		pin 4	222.7	221.6	-1.1	223.1	0.4
		pin 5	226.1	224.2	-1.9	225.7	-0.4
		pin 6	227.8	226.4	-1.4	226.7	-1.1
		pin 7	227.4	225.5	-1.9	225.7	-1.7
		pin 8	220.0	227.8	7.8	218.4	-1.6
		pin 9	225.9	223.3	-2.6	223.8	-2.1
		pin 10	224.0	221.7	-2.3	221.5	-2.5
		pin 11	227.2	224.8	-2.4	226.2	-1.0
		pin 12	226.4	225.1	-1.3	224.9	-1.5
		pin 13	225.0	222.7	-2.3	224.2	-0.8
		pin 14	226.7	224.4	-2.3	225.7	-1.0
		pin 15	224.5	222.8	-1.7	223.2	-1.3
		pin 16	226.3	224.9	-1.4	224.7	-1.6
		pin 17	228.6	228.2	-0.4	227.9	-0.7
		pin 18	219.0	218.2	-0.8	217.1	-1.9
		pin 19	222.7	222.9	0.2	224.1	1.4
		pin 20	226.5	224.0	-2.5	225.9	-0.6
		pin 21	229.0	228.1	-0.9	230.2	1.2
		pin 22	224.2	223.5	-0.7	224.4	0.2
		pin 23	217.5	216.4	-1.1	218.5	1.0
		pin 24	226.4	225.3	-1.1	226.2	-0.2
ΔR1=R(after shock)- R(initial)							
ΔR2=R(after vibration)- R(initial)							

Appendix (Cont.): Data of the resistance after Testing Seq. (c)

Sample No.	Customer No.	Pin No.	LLCR（mΩ）				
			Initial	After shock test	ΔR2	After vibration test	ΔR2
022	C-8	pin 1	230.0	231.5	1.5	231.5	1.5
		pin 2	226.9	225.6	1.3	227.3	0.4
		pin 3	229.9	228.9	1	230.3	0.4
		pin 4	225.8	225.4	0.4	226.8	1
		pin 5	226.8	224.3	2.5	226.3	0.5
		pin 6	228.4	226.7	1.7	228.1	0.3
		pin 7	230.7	228.7	2	228.8	1.9
		pin 8	226.6	223.4	3.2	224.9	1.7
		pin 9	223.8	221.2	2.6	222.7	1.1
		pin 10	223.1	220.2	2.9	222.2	0.9
		pin 11	231.3	228.7	2.6	230.7	0.6
		pin 12	229.0	226.1	2.9	227.8	1.2
		pin 13	226.9	223.2	3.7	225.8	1.1
		pin 14	227.9	220.9	7.0	223.2	4.7
		pin 15	223.5	221.1	2.4	221.8	1.7
		pin 16	229.5	227.1	2.4	227.7	1.8
		pin 17	223.9	221.7	2.2	223.8	0.1
		pin 18	226.1	225.8	0.3	227.3	1.2
		pin 19	231.5	230.1	1.4	233.0	1.5
		pin 20	226.5	225.1	1.4	228.0	1.5
		pin 21	228.5	227.2	1.3	229.9	1.4
		pin 22	222.7	223.3	0.6	223.6	0.9
		pin 23	222.5	220.5	2.0	223.1	0.6
		pin 24	229.6	231.2	1.6	230.4	0.8
ΔR1=R(after shock)- R(initial)							
ΔR2=R(after vibration)- R(initial)							

*** End of report ***

Remark: This report instead of the previous report which No. is SZER100226117714E.